

# terotest

## GX5055

**Dynamically Controlled, 50MHz 6U  
High Speed Digital I/O PXI Card with  
Programmable Level Pin Electronics**



Geotest's GX5055 represents a new level of performance and capabilities for PXI-based digital instrumentation. Based on the proven architecture of the GX5050, the GX5055 cards offer high performance pin electronics and an enhanced timing generator in a compact, 6U PXI form factor. Each card can function as a stand-alone digital subsystem or if required, multiple cards can be interconnected, providing a single domain and supporting up to 512 bi-directional channels. Each digital channel can be individually programmed for a drive hi, drive lo, sense hi, sense lo, and a load value – offering the user complete flexibility when creating test programs and fixtures for multiple UUTs.

### Legacy ATE replacement:

When used as part of a GBATS or iTest solution and in conjunction with Geotest's LASAR linked DtifEasy software toolset, the GX5055 card offers a cost-effective solution for the replacement of various legacy systems, including:

- Genrad 1795, 1796, 2225, 2235, 2750
- Hewlett Packard DTS-70
- Teradyne L200 and L300
- Schlumberger 730 and 790

### Key Features:

- Cycle based, dynamic digital card
- Per pin programmability & direction control
- Per channel Parametric Measurement Unit
- Dual level drive / sense
- Adjustable slew rate from .1 to 1 V/ns
- Drive / sense voltage range of -10 V to + 15 V
- Per channel de-skew
- Full support for LASAR simulated Go / No Go test patterns, Guided Probe and Fault Dictionary via DtifEasy software
- Supports 6 data formats
- 50 MHz vector rate
- 32 bi-directional I/O pins
- Up to 512 pins when cards are daisy chained
- 10 MB of on-board memory
- External, programmable internal clock rates
- Clock rates from 5Hz to 50MHz

### Applications:

- High-speed functional digital test
- Fault finding via Guided Probe & Fault Dictionary
- Vector capture
- Device testing, hybrid and digital
- Memory testing
- LRU and SRU test
- Ideal for legacy ATE replacement of various test systems when used as part of a GBATS or iTest solution together with DtifEasy software.

### Guided Probe & Fault Dictionary

The guided probe consists of 3 channels from the digital hardware - a digital probe, a momentary push button and a status indicator. The probe is compatible with both the GX5055 and GX529x digital cards and provides the probed UUT states for the guided probe sequence, and can use the fault dictionary files to reduce the time needed to locate a faulty component.



If you thought you couldn't test it.....  
.....talk to us !

Tel: +44 (0) 1462 742499  
Email: [info@terotest.com](mailto:info@terotest.com)

[www.terotest.com](http://www.terotest.com)